

# RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS12885	May-96	9617 A2	HYUNDAI	DL607533AAI	1.2μ OX/NI	24 SOIC

**STRESS/JOB NO.**

**READPOINT  
(Sample Size/No. of Fails)**

Preconditioning (P/C): HTC Vapor Phase P-17523		<u>Electrical</u> 233/0	<u>Cum %</u> 0.0%
Sonoscan P-17543		<u>Post Vapor Phase</u> 2/0	
Infant / High Voltage Life 125°C, 7.0 V. P-17544, P-17640	<u>48 Hr</u> 231/0	<u>336 Hr</u> 77/0	<u>1KHr</u> 77/0
			<u>*Failure Rate</u> 30 Fits
*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0			
Temp Cycle -55°C to +125°C P-17641	<u>300 ~</u> 39/0	<u>1K ~</u> 39/0	<u>Cum %</u> 0.0%
Biased Moisture 85°C/85% RH, 5.5 V. P-17642	<u>274 Hr</u> 77/0	<u>959 Hr</u> 77/0	<u>Cum %</u> 0.0%
Autoclave 121°C/100% RH, 2 Atmos P-17643		<u>96 Hr</u> 38/0	<u>Cum %</u> 0.0%

**Failure Mode**

**Failure Analysis**